



DR YIELD Releases new Product Module for Coherence Analysis of Factory Events and Yield Degradation

DR YIELD's Event Control Module brings fast and efficient coherence analysis of events and production failures.

GRAZ, AUSTRIA, April 26, 2016 /EINPresswire.com/ -- The [Event Control Module](#) (ECM) allows the analysis, detection and automatic notification of effects introduced by factory events, such as equipment supply changes, maintenance events or similar.

"The ECM is based directly on our customers' input and perfectly augments our existing yield management solution [YieldWatchDog 3.5](#)", says CEO Dieter Rathei. "Every year we hear about a major yield excursion caused by contaminated chemical supply, a tool maintenance gone wrong or the like. By employing the ECM, we can now track all changes happening during chip manufacturing and testing. But that is not all – the ECM automatically informs you when any problems or significant changes are detected. In the end, the module does not only improve our customers' workflow and save our customers time and money – it also saves them a lot of energy and frustration needed for backtracking the root cause."

New Event Control Module features at a glance:

- Analysis and control of factory events like tool maintenance, supply changes etc.
- Also applicable for events on the test floor such as probe card changes and the like
- Intuitive display of statistics before and after these events
- Analysis and control on factory or equipment level
- Automatic notification if significant changes are detected after an event
- Users can set up event-parameter relations and configure for which events they wish to get notifications.

Get more information about all the functions and possibilities of YieldWatchDog at www.dryield.com/product

About [DR YIELD](#)

DR YIELD software & solutions GmbH is a technology leading company in dealing with Big Data for the semiconductor industry. It serves customers worldwide as an innovative provider of next-generation software for yield control. The patented software solution YieldWatchDog enables monitoring of all manufacturing data and allows early detection of potential production problems at an unprecedented level of thoroughness. Thus, costly yield excursions can be avoided due to early notifications.

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